

## Supporting Information

### Force Spectroscopy of Quadruple H-Bonded Dimers by AFM: Dynamic Bond Rupture and Molecular Time-Temperature Superposition

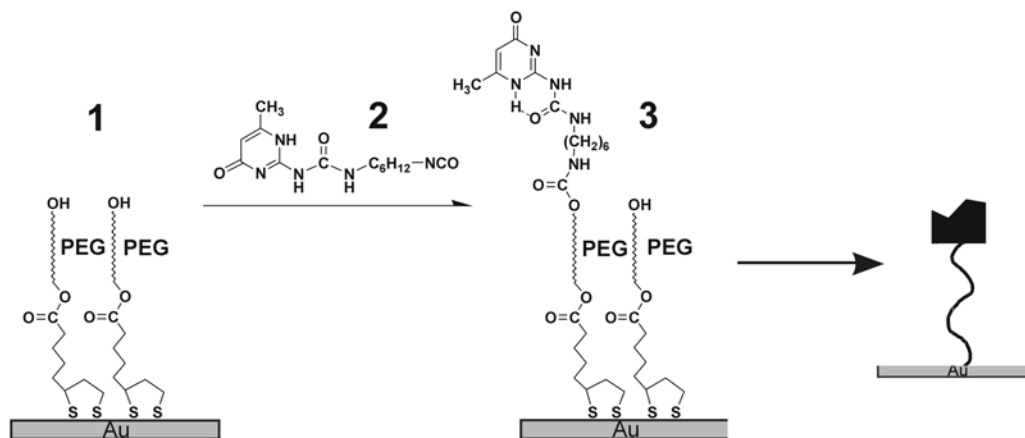
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#### Experimental

##### Materials.<sup>[S1-S3]</sup>

For the synthesis of 1,2-dithiolane-3-pentyl-derivatized PEG **1**, UPy isocyanate **2**, and PEG-UPy disulfide **3** on Au (Scheme S1), see reference [S1].



**Scheme S1.** Formation of PEG linked 2-ureido-4[1H]-pyrimidinone moieties at Au(111) surfaces.

##### Preparation of Substrates and Self-assembled Layers.<sup>[S1,S2]</sup>

Gold substrates ( $11 \times 11 \text{ mm}^2$ , 250 nm Au on 2 nm Cr on borosilicate glass) for SMFS measurements were purchased from Metallhandel Schröer GmbH (Lienen, Germany). Au(111) samples were obtained by annealing these substrates in a high purity  $\text{H}_2$  flame for 5 minutes [S1]. Prior to use, these substrates were cleaned in piranha solution (3:1  $\text{H}_2\text{SO}_4$ :  $\text{H}_2\text{O}_2$  (30%) by volume), then rinsed with MilliQ water and ethanol and dried in a nitrogen stream. ***Caution: Piranha solution should be handled with extreme caution: it has been reported to detonate unexpectedly.*** Self-assembled layers were formed, as described in ref. [S1] by immersing the

gold substrates into 1 mM solutions of **1** in CH<sub>2</sub>Cl<sub>2</sub> for 10 hours. The surface reaction shown in Scheme S1 was carried out after rinsing with pure solvent as described in ref. [S1]. After rinsing with pure solvent and drying in an N<sub>2</sub> stream,<sup>2</sup> measurements were performed with minimal delay.

**AFM and Tip Modification.** The AFM measurements were carried out with a NanoScope IIIa multimode AFM (Veeco / Digital Instruments (DI), Santa Barbara, CA) in hexadecane (Aldrich) utilizing a liquid cell (DI). Triangular shaped silicon nitride cantilevers and silicon nitride tips (DI) coated with ca. 2 nm Ti and ca. 50 nm Au in high vacuum (SSENS b.v., Hengelo, the Netherlands) were functionalized as described above with **3**. The cantilever spring constants were calibrated by the thermal noise method as described in reference [S1]. The cantilever used in the experiment shown in Figures 1 and 2 had a spring constant of  $0.094 \pm 0.014$  N/m.

The loading rate was directly determined from the slope of the force-extension curve near the rupture point. For instance, the force values for the last *n* data points (just before the rupture point) are easily measured on the force-extension curve. From the piezo ramp rate the corresponding time for each data point can be calculated. Thus, the force (in pN) of these *n* data points can be plotted against time (in seconds). A linear least squares fit of these data points affords the loading rate in pN/s.

The temperature of the liquid inside the liquid cell was controlled by a custom-made heating device [S4]. This heating device is based on a Peltier element (type TEC1 C-24.0-5.0-23/78-xy; size 6 × 6 mm<sup>2</sup>; Eureka Messtechnik GmbH, Germany) attached with epoxy glue (thermal conductivity 0.0002 W/cm K) onto an AFM sample disk. Gold substrates were attached directly over the Peltier element by paper glue (Pritt type Glue-it, Henkel, Germany). The Peltier was connected to a DC power supply (Delta Elektronika) and a Fluke 52 II Thermometer using a K type thermocouple probe (Fluke). The electrical and temperature measurements were performed using a DMM 3020 Digital Multimeter (Kontron Electronic). The temperature calibration of the heating device in air was performed using *n*-alkanoic acids (decanoic, dodecanoic, tetradecanoic and hexadecanoic acid, Aldrich) with known melting points. The temperature calibrations in hexadecane for the liquid cell AFM set-up were performed by measuring the respective temperature for different applied currents using a thermocouple.

### **Analysis of Rupture Forces of Quadruple Hydrogen Bonds<sup>[S1]</sup>**

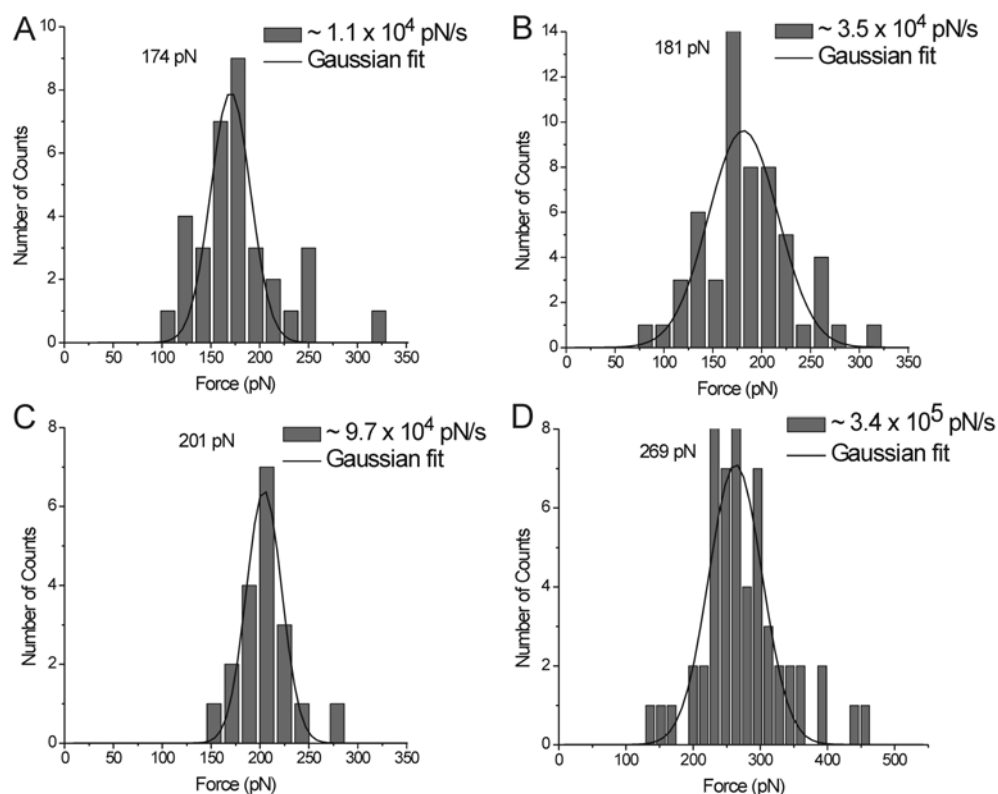
Quadruple H-bonding interactions in individual (UPy)<sub>2</sub> complexes were probed by SMFS between PEG linked UPy (**3**) immobilized both on Au(111) and gold-coated AFM tips

functionalized with **3**. The force - extension data were fitted with the m-FJC model (Equation S1), for details see reference S1:

$$x(F) = \left[ \coth\left(\frac{FI_K}{k_B T}\right) - \frac{k_B T}{FI_K} \right] \left[ L_{\text{contour}} + \frac{n}{K_{\text{segment}}} F \right] \quad (\text{S1})$$

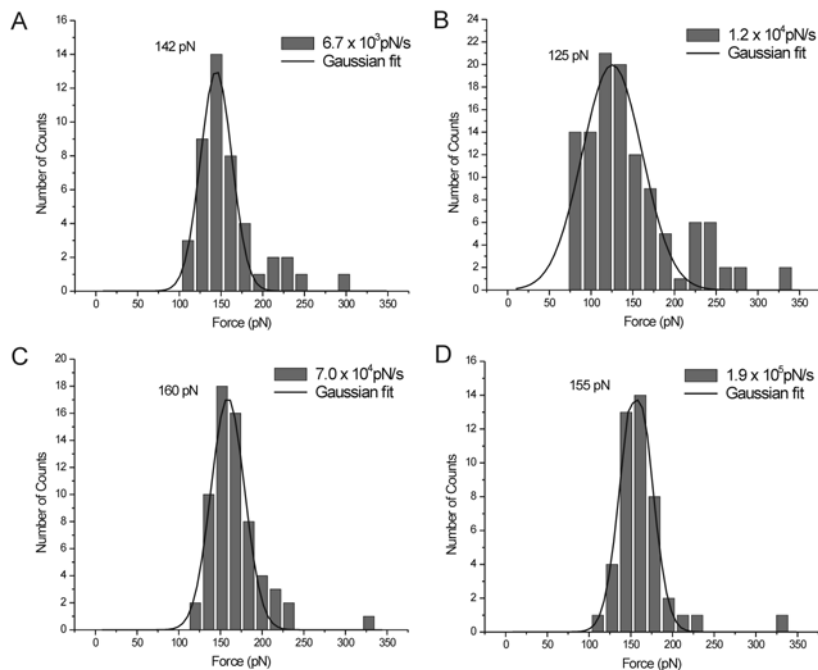
where  $x$  is the extension of the polymer chain;  $F$  is the applied force;  $I_K$  (Kuhn length) is the length of the statistically independent segment;  $n$  is the number of segments, which equals  $L_{\text{contour}}/I_K$ ;  $K_{\text{segment}}$  is the segment elasticity, which characterizes the deformability of the segment;  $k_B$  is the Boltzmann constant; and  $T$  is the temperature.

### Rupture Forces at 301 K



**Figure S1.** Histograms of pull-off forces of individual (UPy)<sub>2</sub> complexes at loading rates of (A)  $1.1 (\pm 0.2) \times 10^4$  pN/s, (B)  $3.5 (\pm 0.7) \times 10^4$  pN/s, (C)  $9.7 (\pm 1.9) \times 10^4$  pN/s, and (D)  $3.4 (\pm 0.7) \times 10^5$  pN/s at 301 K in hexadecane. The solid lines in (A) – (D) are Gaussian fits to the corresponding histograms.

## Rupture Forces at 330 K



**Figure S2.** Histograms of rupture forces of individual (UPy)<sub>2</sub> complexes determined at 330 K in hexadecane at loading rates of (A)  $6.7 (\pm 1.3) \times 10^3$  pN/s, (B)  $1.2 (\pm 0.2) \times 10^4$  pN/s, (C)  $6.9 (\pm 1.4) \times 10^4$  pN/s, and (D)  $1.9 (\pm 0.4) \times 10^5$  pN/s. The solid lines are Gaussian fits to the corresponding histograms.

## References

- [S1] Zou, S.; Schönherr, H.; Vancso, G. J. *Angew. Chem. Int. Ed.* **2005**, *44*, 956-959.
- [S2] Zou, S.; Zhang, Z. H.; Förch, R.; Knoll, W.; Schönherr, H.; Vancso, G. J. *Langmuir* **2003**, *19*, 8618-8621.
- [S3] Folmer, B. J. B.; Sijbesma, R. P.; Versteegen, R. M.; van der Rijt, J. A. J.; Meijer, E. W. *Adv. Mater.* **2000**, *12*, 874-878.
- [S4] Zou, S.; Vera Marín, I. J.; Schönherr, H.; Vancso, G. J. *manuscript in preparation*.